



MAIL STOP AF  
PATENT  
8008-1050

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Hiroyoshi KUGE et al.

Conf. 3414

Application No. 10/786,552

Group 2825

Filed February 26, 2004

Examiner L. Garbowski

SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE  
AND DESIGN AUTOMATION APPARATUS, BOUNDARY  
SCAN TEST METHOD AND PROGRAM

AMENDMENT AFTER FINAL REJECTION

Assistant Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

April 4, 2007

Sir:

In response to the Official Action of January 18, 2007,  
please amend the above-identified application as follows:

**Amendments to the Specification** begin on page 2 of this  
paper.

**Amendments to the Claims** are reflected in the listing  
of claims that begins on page 4 of this paper.

**Remarks** begin on page 9 of this paper.

OK to  
enter  
MD 4/4/07